

STW240NF55

N-CHANNEL 55V - 0.0027 Ω - 120A TO-247 STripFET™ II POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D (1)
STW240NF55	55V	$<$ 0.0035 Ω	120A

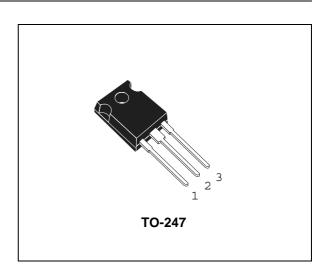
- TYPICAL $R_{DS}(on) = 0.0027\Omega$
- STANDARD THRESHOLD DRIVE
- 100% AVALANCHE TESTED

DESCRIPTION

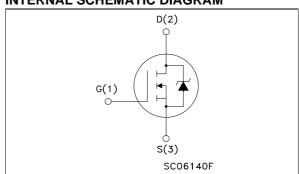
This Power MOSFET is the latest development of STMicroelectronis unique "Single Feature Size™" stripbased process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment therefore a remarkable manufacturing reproducibility.

APPLICATIONS

- HIGH CURRENT, HIGH SWITCHING SPEED
- OR-ING FUNCTION



INTERNAL SCHEMATIC DIAGRAM



Ordering Information

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SALES TYPE	MARKING	PACKAGE	PACKAGING
STW240NF55	W240NF55	TO-247	TUBE

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	55	V
V_{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	55	V
V _{GS}	Gate- source Voltage	± 20	V
I _D (1)	Drain Current (continuous) at T _C = 25°C	120	А
I _D (1)	Drain Current (continuous) at T _C = 100°C	120	А
I _{DM} (●)	Drain Current (pulsed)	480	А
P _{tot}	Total Dissipation at T _C = 25°C	500	W
	Derating Factor	3.33	W/°C
dv/dt (2)	Peak Diode Recovery voltage slope	5	V/ns
E _{AS} (3)	Single Pulse Avalanche Energy	3.5	J
T _{stg}	Storage Temperature	-55 to 175	°C
Tj	Operating Junction Temperature	-55 to 175	

^(•) Pulse width limited by safe operating area. (1)Current Limited by Package

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(2) $I_{SD} \le 120A$, di/dt $\le 600A/\mu s$, $V_{DD} \le 48V$, $T_j \le T_{JMAX}$. (3) Starting $T_j = 25$ °C, $I_D = 60A$, $V_{DD} = 30V$

THERMAL DATA

Rthj-amb Tl Thermal Resistance Junction-ambient Max 50 Maximum Lead Temperature For Soldering Purpose Typ 300 (1.6 mm from case, for 10 sec)	°C/W °C/W °C			Maximum Lead Temperature For Soldering Purpose	Rthj-amb T _I
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ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

OFF

Symbol	Parameter Test Conditions		Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	55			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating T_{C} = 125°C			1 10	μA μA
Igss	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 20V			±100	nA

ON (*)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I _D = 250 μA	2		4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V	I _D = 60 A		2.7	3.5	mΩ

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	$V_{DS} = 15 \text{ V}$ $I_{D} = 60 \text{ A}$		100		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V$, $f = 1 MHz$, $V_{GS} = 0$		12250 2600 745		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time	$\begin{aligned} &V_{DD} = 27.5 \text{ V} &I_{D} = 60 \text{ A} \\ &R_{G} = 4.7 \ \Omega &V_{GS} = 10 \text{ V} \\ &(\text{Resistive Load, Figure 3}) \end{aligned}$		52 235		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} =27.5V I _D =120A V _{GS} =10V		350 75 140	480	nC nC nC

SWITCHING OFF

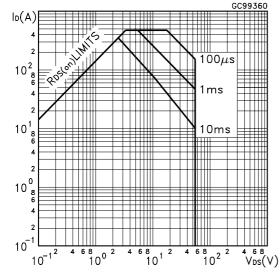
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time	$\begin{split} V_{DD} &= 27.5 \text{ V} & I_D = 60 \text{ A} \\ R_G &= 4.7 \Omega, & V_{GS} = 10 \text{ V} \\ \text{(Resistive Load, Figure 3)} \end{split}$		225 115		ns ns

SOURCE DRAIN DIODE

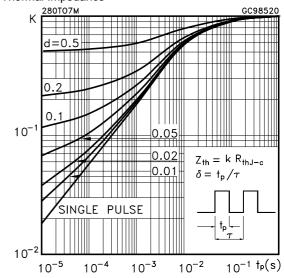
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} (•)	Source-drain Current Source-drain Current (pulsed)				120 480	A A
V _{SD} (*)	Forward On Voltage	I _{SD} = 120 A V _{GS} = 0			1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 120 \text{ A}$ di/dt = 100A/µs $V_{DD} = 20 \text{ V}$ $T_j = 150 ^{\circ}\text{C}$ (see test circuit, Figure 5)		115 435 7.6		ns nC A

^(*)Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.
(•)Pulse width limited by safe operating area.

Safe Operating Area

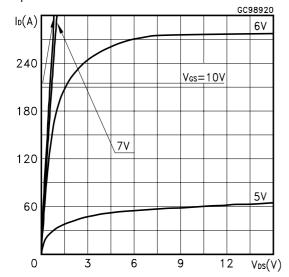


Thermal Impedance

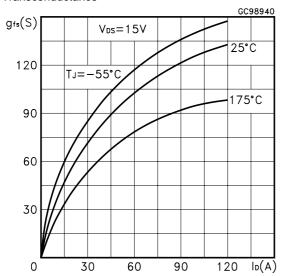


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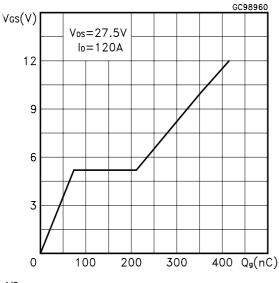
Output Characteristics



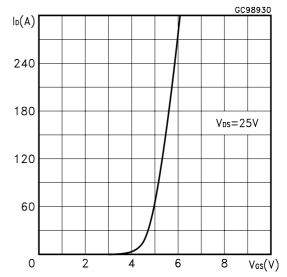
Transconductance



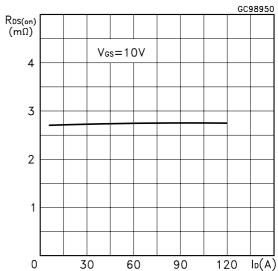
Gate Charge vs Gate-source Voltage



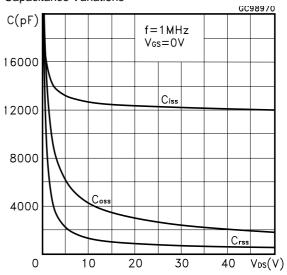
Transfer Characteristics



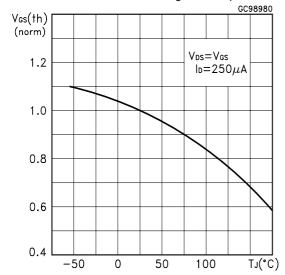
Static Drain-source On Resistance



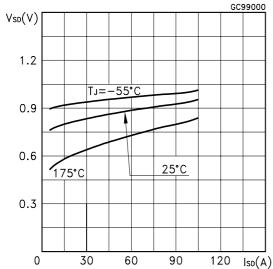
Capacitance Variations



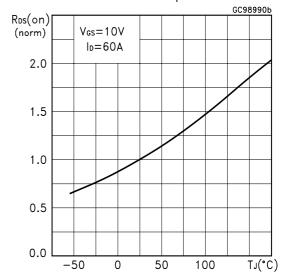
Normalized Gate Threshold Voltage vs Temperature



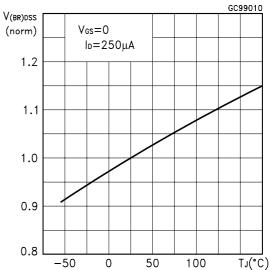
Source-drain Diode Forward Characteristics



Normalized on Resistance vs Temperature



Normalized Breakdown Voltage vs Temperature



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Fig. 1: Unclamped Inductive Load Test Circuit

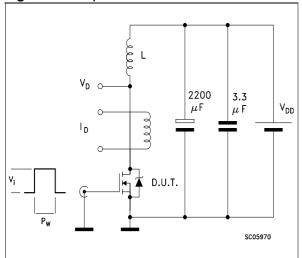


Fig. 3: Switching Times Test Circuits For Resistive Load

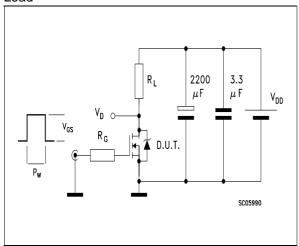


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

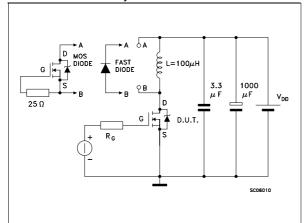


Fig. 2: Unclamped Inductive Waveform

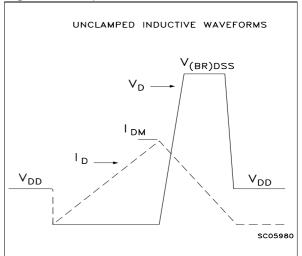
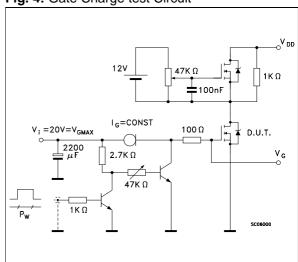
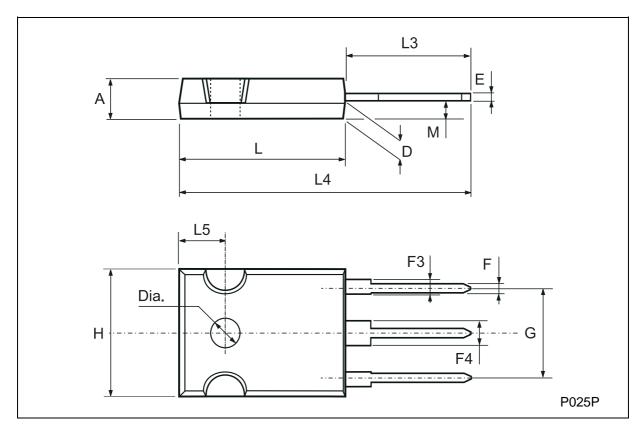


Fig. 4: Gate Charge test Circuit



TO-247 MECHANICAL DATA

DIM.		mm			inch	
Dilvi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	4.7		5.3	0.185		0.209
D	2.2		2.6	0.087		0.102
Е	0.4		0.8	0.016		0.031
F	1		1.4	0.039		0.055
F3	2		2.4	0.079		0.094
F4	3		3.4	0.118		0.134
G		10.9			0.429	
Н	15.3		15.9	0.602		0.626
L	19.7		20.3	0.776		0.779
L3	14.2		14.8	0.559		0.582
L4		34.6			1.362	
L5		5.5			0.217	
М	2		3	0.079		0.118



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